· · · · · · · · · · · · · · · · · · ·	Application No.	Applicant(s)	
Notice of Allowability	10/661,720 Examiner	FANG, SHENQING Art Unit	
	Andy Huynh	2818	
The MAILING DATE of this communication appe All claims being allowable, PROSECUTION ON THE MERITS IS ( herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGOT ( of the Office or upon petition by the applicant. See 37 CFR 1.313	ars on the cover sheet was OR REMAINS) CLOSED or other appropriate commodities. This application is	ith the correspondence address n this application. If not included unication will be mailed in due course. Th	
1. X This communication is responsive to the Amendment dated	1 03/29/2005.		
2. X The allowed claim(s) is/are <u>8-14</u> .			
3. $\boxtimes$ The drawings filed on <u>29 March 2005</u> are accepted by the E	Examiner.		
4. Acknowledgment is made of a claim for foreign priority un  a) All b) Some* c) None of the:  1. Certified copies of the priority documents have  2. Certified copies of the priority documents have  3. Copies of the certified copies of the priority documents have  International Bureau (PCT Rule 17.2(a)).  * Certified copies not received:  Applicant has THREE MONTHS FROM THE "MAILING DATE" of noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.  5. A SUBSTITUTE OATH OR DECLARATION must be submit INFORMAL PATENT APPLICATION (PTO-152) which give comply comply will result in the submit information of the complex process.	been received. been received in Application and this communication to file ENT of this application.  tted. Note the attached EX is reason(s) why the oath of the second in	on No  Id in this national stage application from the stage application from the stage application from the stage application from the stage are ply complying with the requirements and the stage application from the stage applica	<b>S</b>
(a) ☐ including changes required by the Notice of Draftsperson  1) ☐ hereto or 2) ☐ to Paper No./Mail Date  (b) ☐ including changes required by the attached Examiner's Paper No./Mail Date  Identifying indicia such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in the paper No./Mail Open Should be labeled as such in the paper No./Mail DEPOSIT OF and/or INFORMATION about the deposit	on's Patent Drawing Revie Amendment / Comment on 84(c)) should be written on he header according to 37 C	r in the Office action of he drawings in the front (not the back) of FR 1.121(d).	
attached Examiner's comment regarding REQUIREMENT F			
Attachment(s)  1. Notice of References Cited (PTO-892)  2. Notice of Draftperson's Patent Drawing Review (PTO-948)  3. Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date  4. Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ☐ Interview S Paper No 7. ☑ Examiner's 8. ☑ Examiner's 9. ☐ Other	Informal Patent Application (PTO-152) Summary (PTO-413), /Mail Date S Amendment/Comment Statement of Reasons for Allowance	

## **DETAILED ACTION**

In the Amendment dated March 29, 2005, the specification, the title, Figure 3 of the drawing, and claims 8, 10, 11 and 14 are amended is acknowledged.

## Examiner's Amendment

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The application has been amended as follows:

This application is in condition for allowance except for the presence of non-elected claims 1-7 and 15-20 without traverse. Accordingly, claims 1-7 and 15-20 have been canceled.

## Allowable Subject Matter

Claims 8-14 are allowed.

The following is an examiner's statement of reason for allowance:

Claims 8-14 are allowable over the prior art of record because the prior art of record does not teach or render obvious a memory cell comprises a source component formed by implantation of a dopant and diffusion of the dopant from a silicide in a source metal contact region, and a drain component formed by implantation of a dopant and diffusion of the dopant

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from the silicide in a drain metal contact region, and in combination with all other features as recited in independent claim 8.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance".

## Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Andy Huynh whose telephone number is (571) 272-1781. The examiner can normally be reached on Monday-Friday 8:30am-5:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Nelms can be reached on (571) 272-1787. The fax phone numbers for the organization where this application or proceeding is assigned are (703) 872-9306 for regular communications and (703) 872-9306 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR

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system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR

system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

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04/14/05

Andy Huynh

Patent Examiner